

Beam-test data analysis using the integration method for SNR estimation

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Overview

- Beam-test
- My objective - estimate SNR
- Signal shape function
- Fit function parameters
- Methods to estimate signal to noise ratio
- Conclusions

2011 Beam-Test

Measurements performed at DESY 22 electron beam

BeamCal module contains :

- GaAs sensors
- kapton foil
- front-end ASICs (32 channels)
- multichannel ADC SoC ASICs (32 channels)
- data concentrator implemented in FPOAQ 1C
- power pulsing circuit and digitally controlled and monitored biasing and powering circuits.

Goal - behaviour of the complete multichannel BeamCal module in electron beam available at DESY

The collected data allow to determine the performance of the whole readout chain:

- sensor pad uniformity
- gain
- offset and noise
- readout electronics channel uniformity
- crosstalk between channels
- charge sharing in area between sensor pads
- response to electromagnetic shower development generated by tungsten plates included in front of tested module.

My objectives

- Estimate SNR using the integral of the recorded signal
- Fit each signal with signal shape function - extract baseline, amplitude, shaping time, starting time, peaking time (parameters of the signal shape function)
- Calculate the integral of the signal and estimate SNR:

$$S/N = \frac{Signal}{\sigma_{Pedestal}} = \frac{MPV_{Spectrum} - mean_{pedestal}}{\sigma_{Pedestal}}$$

Results obtained for:

- Channel 9 (Pad 10) – high gain (asynchronous and synchronous mode)
- Channel 5 (Pad 6) – low gain

Signal shape function

$$s(t) = V_0 \frac{t}{\tau} e^{-t/\tau}$$

In root: $p[0] + p[1] * (x - p[2]) / p[3] * TMath::Exp(-(x - p[2]) / p[3])$

- | | |
|-------------------------|---|
| – p[0] : y-offset | -> baseline |
| – p[1] : norm | -> V0 * amplification |
| – x-p[2]: relative time | -> p[2] = time when signal (fit) starts |
| – p[3] : | -> time constant (τ), shaping time |

Fitting parameters

➤ Maximum:

$$t = \tau$$

➤ Amplitude:

$$A = s(t = \tau) = V_0 \exp(-1) \Rightarrow V_0 = A * e \rightarrow \underline{V_0 \text{ is "Norm"}} = \text{Real Amplitude} * e$$

➤ Area under the curve (integral):

$$F(a) = V_0 (\exp(-a/\tau)(a + \tau) - \tau)$$

$$F_{Ges} = V_0 \lim_{a \rightarrow \infty} (\exp(-a/\tau)(a + \tau) - \tau) = V_0 * \tau \quad (\text{MPV_Norm} * \text{Mean}_\tau)$$

Fit Procedure and constraints

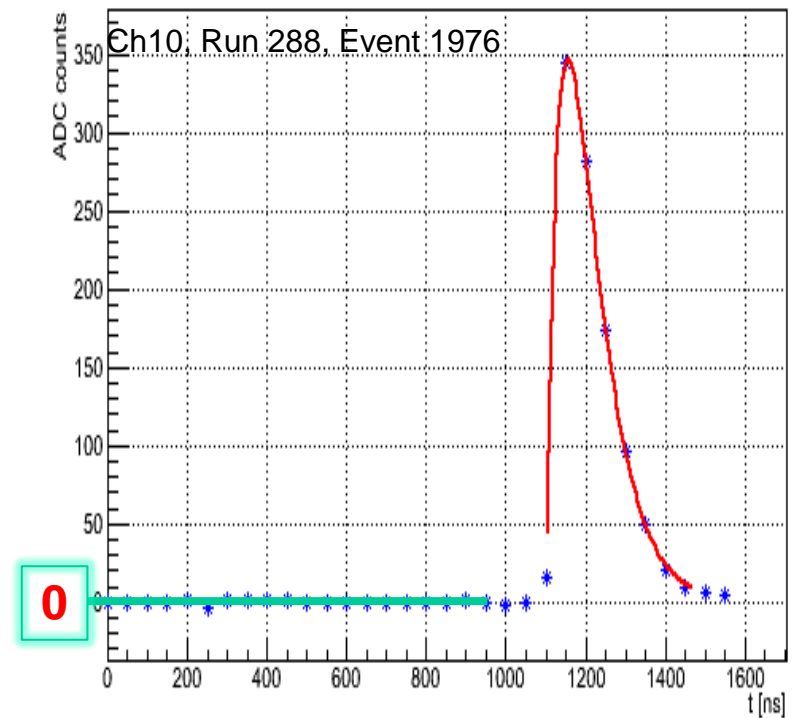
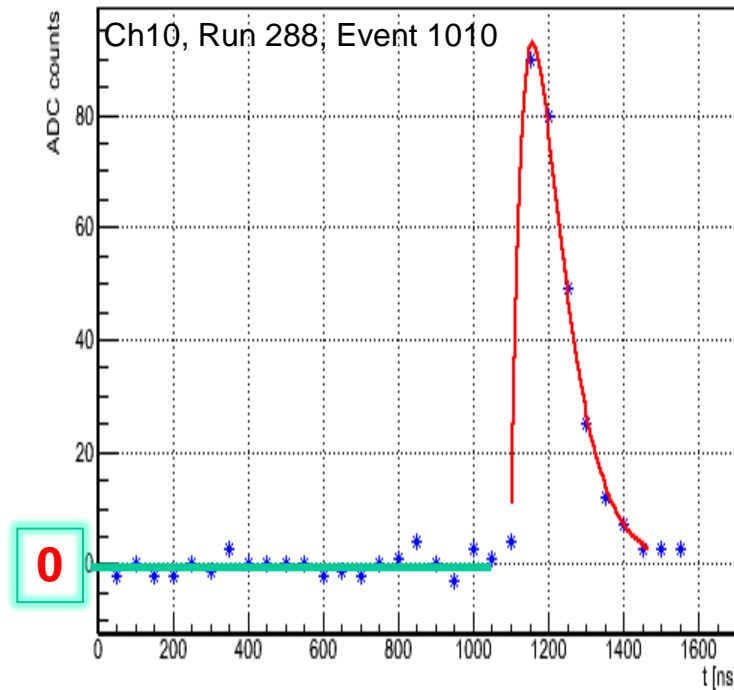
CMN + Pedestal subtraction included

Then, fit if:

Signal $> 5 * \sigma_{pedestal}$

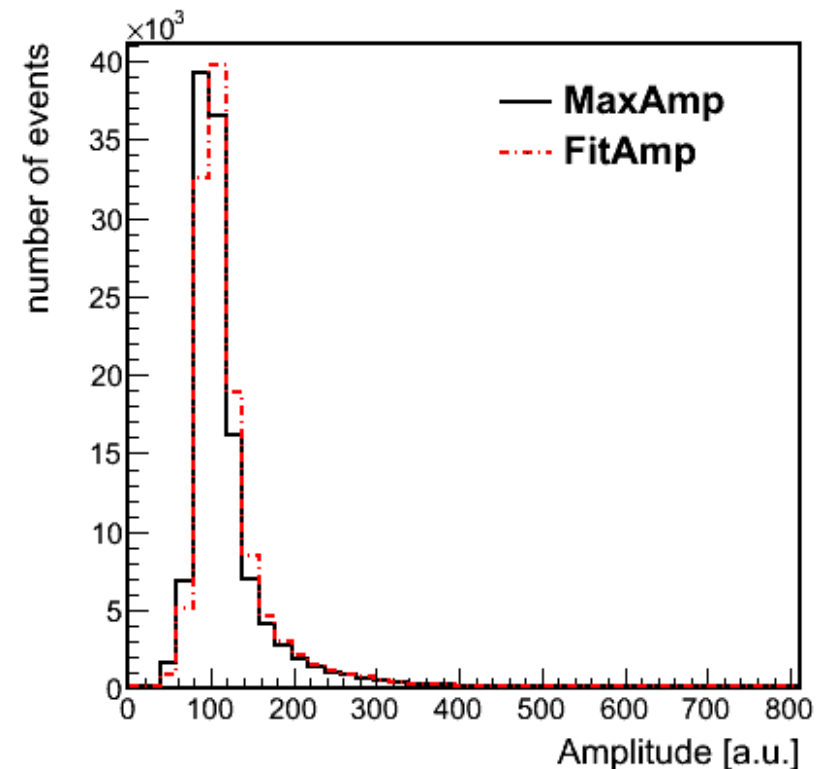
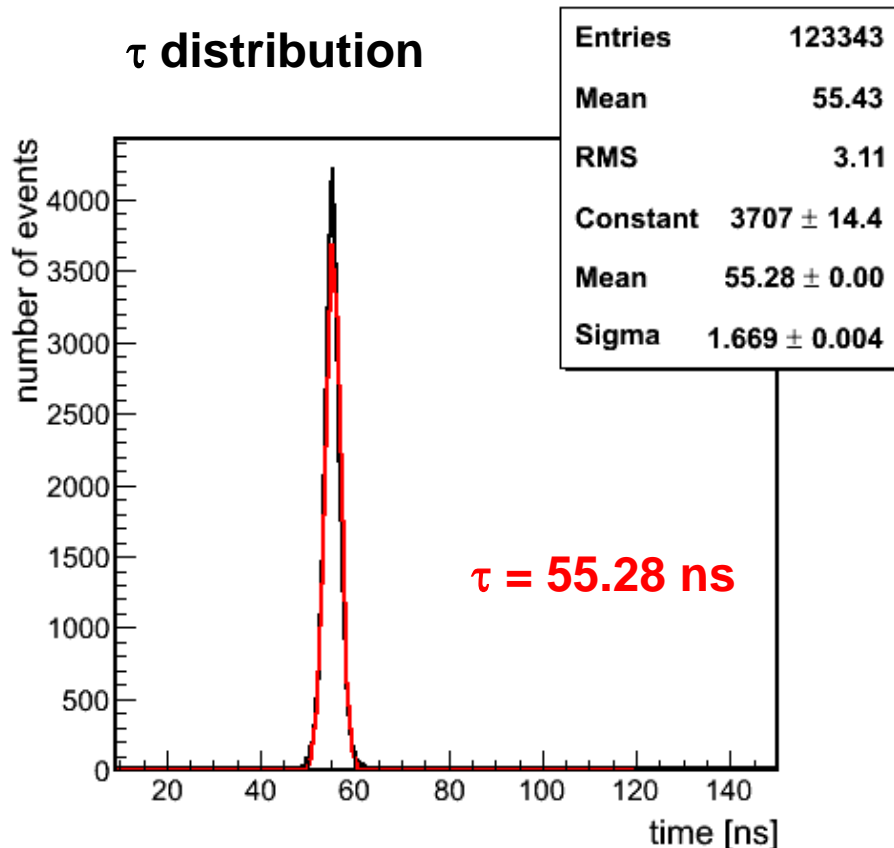
Relative Parameter Error $< 50\%$

Search for fit_start (mean over 7 samples $> 5 * \sigma_{pedestal}$)



Parameters distributions after the fit

Channel 9 – Asynchronous Mode



————— Maximum Amplitude (taken from the data)

- . - . - . - . Amplitude given by the fit

$A \neq \text{Norm! (Norm=A*e)}$

Integration window – graphical solution

Range: (Start time (from the fit) ; Start time + a)

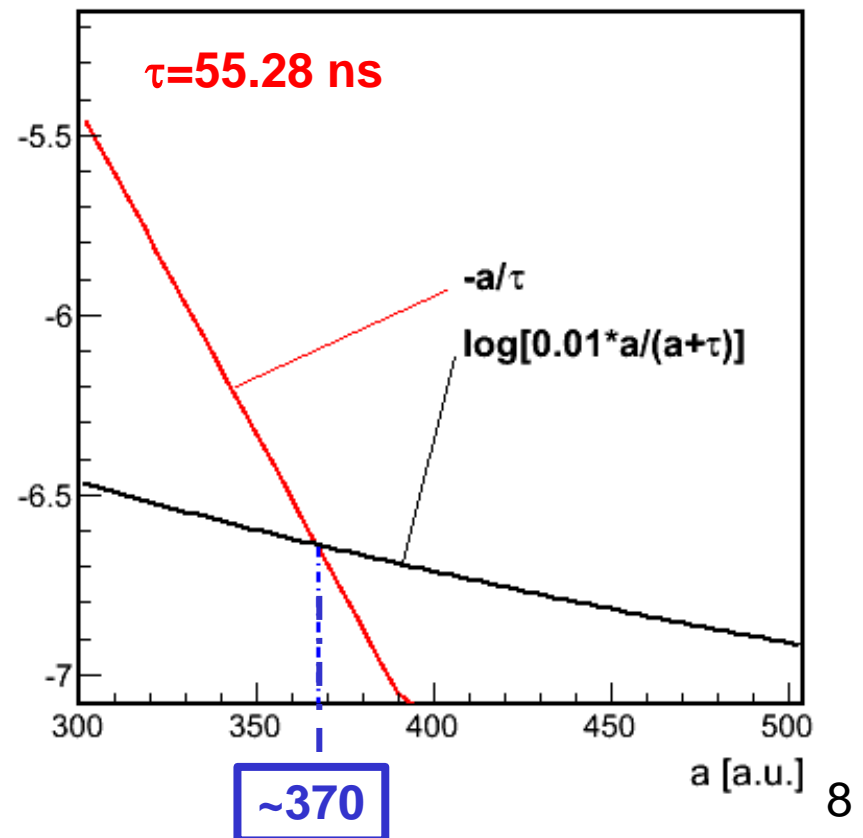
“a” = integration window: when area under the curve reaches 99% of it's (theoretical) maximum

Graphical solution -solve:

$$\ln\left(\frac{0.01 * t}{a + t}\right) = -\left(\frac{a}{t}\right)$$

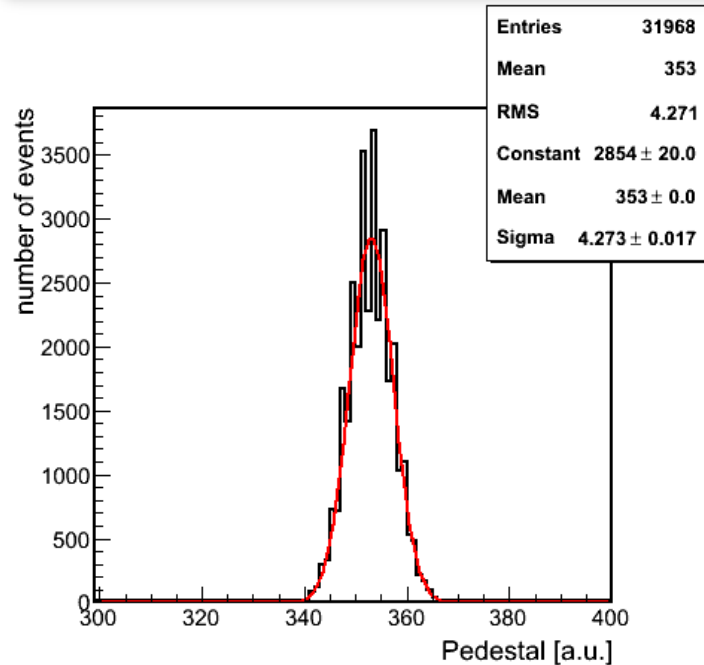
a~370 ns:

- **Integration window ~7 samples**
- **Same window used to calculate pedestal**



Parameters distributions after the fit

Channel 9 – Asynchronous Mode

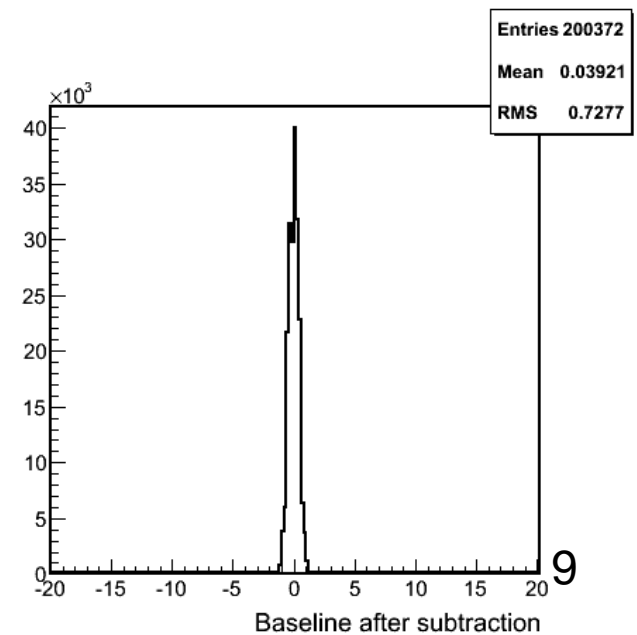
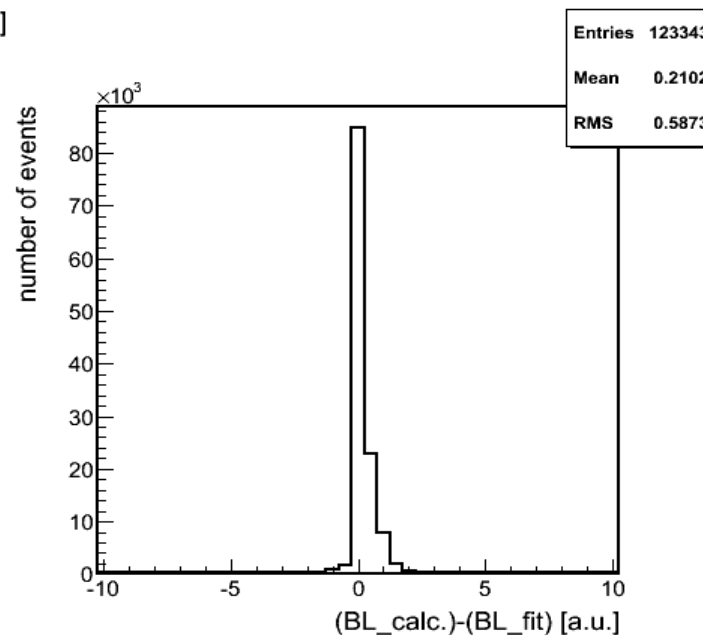


Pedestal distribution, samples 1-7:

$$\text{mean}_{\text{pedestal}} = 353$$

$$\sigma_{\text{pedestal}} = 4.27$$

Difference between
calculated baseline and
baseline given by the fit
- Positive shift



Calculate SNR

1. Extract “Norm” and τ for each event

- Build the “Norm” and τ distributions and extract MPV_Norm and Mean_ τ

$$F(a) = V_0 * \tau$$

$$S/N = \frac{MPV_{Norm} * \tau_{mean}(ADC_{counts} * sample)}{\sigma_{Pedestal}}$$

2. Calculate integral for each event

$$F(a) = V_0 (\exp(-a / \tau)(a + \tau) - \tau) \text{ (“a” is the integration window)}$$

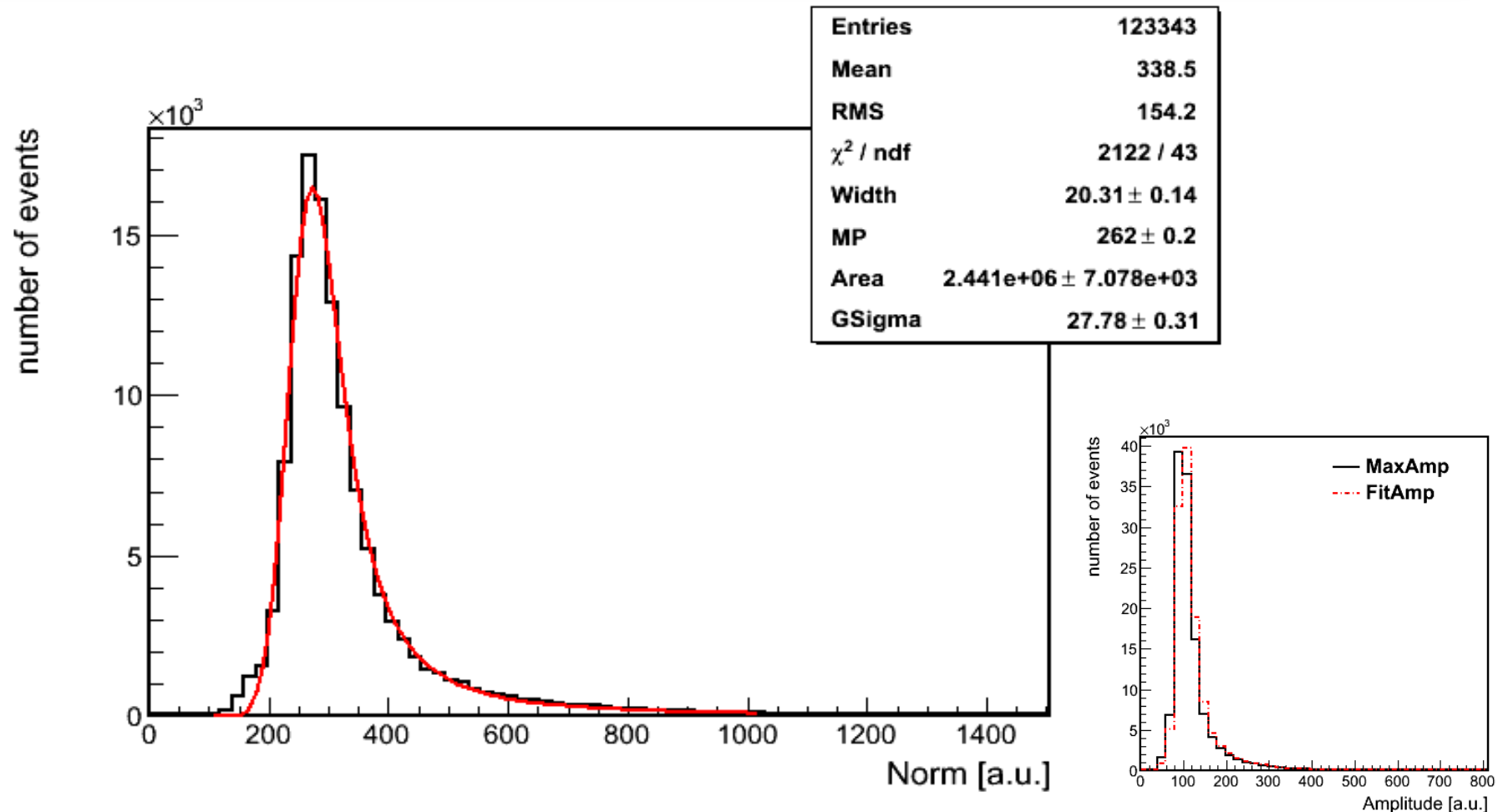
$$S/N = \frac{MPV_{Integral} (ADC_{counts} * sample)}{\sigma_{Pedestal}}$$

3. Calculate SNR for each event, build SNR distribution:

$$S/N = MPV_{SNR}$$

1. “Norm” Distribution

Channel 9 – Asynchronous Mode

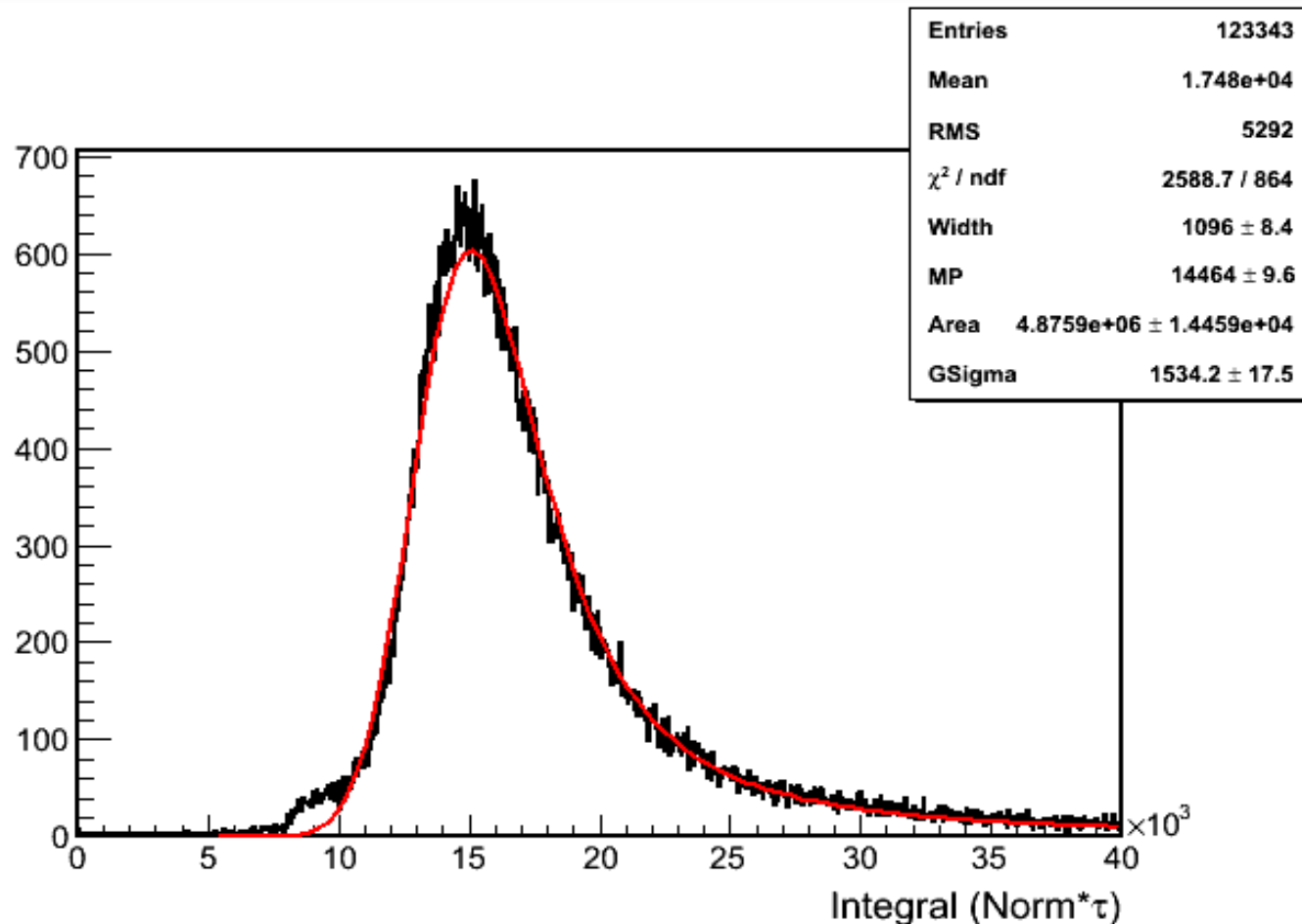


$$\begin{aligned}\text{MPV_Signal_Size (Area)} &= \text{MPV_Norm} * \text{Tau} \\ &= 262 * 55.28 = 14483.36 \text{ ADC_counts*ns} \\ &= 289.67 \text{ ADC_counts*sample}\end{aligned}$$

$$\text{S/N} = 289.67 / 4.27 = 67.83$$

2. Integral distribution

Channel 9 – Asynchronous Mode

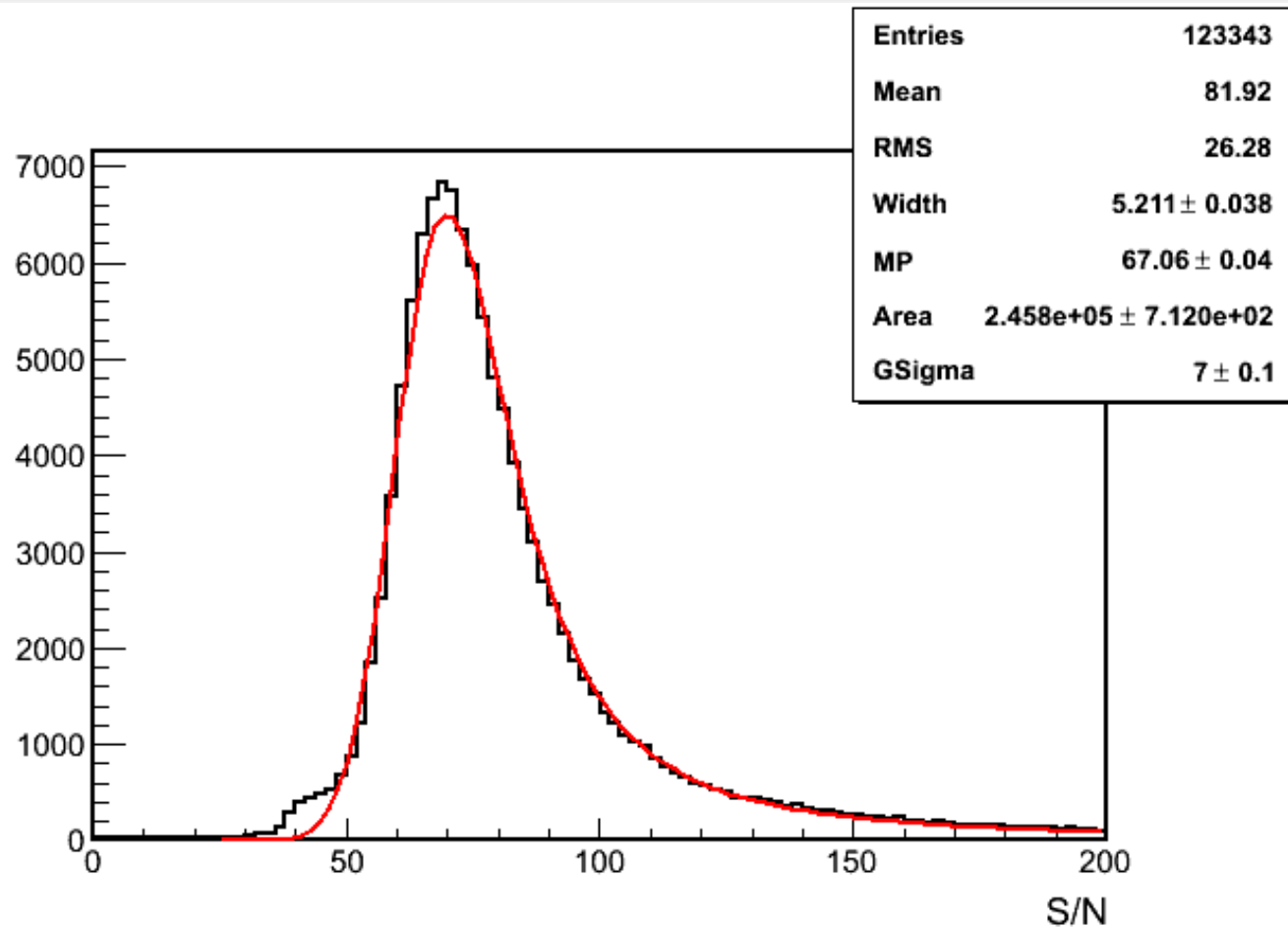


MPV_Signal_Size (**Area**) = MPV_Integral
= 14464 ADC_counts*ns
= 289.28 ADC_counts*sample

$$S/N = 289.28 / 4.27 = 67.74$$

3. SNR distribution

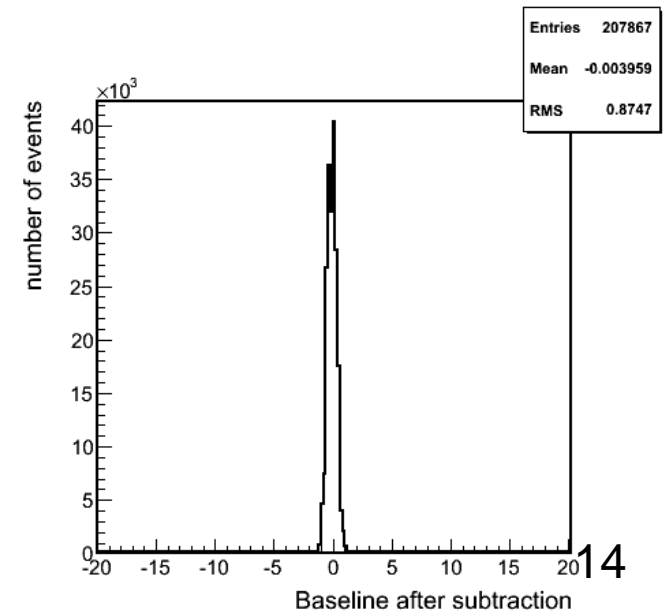
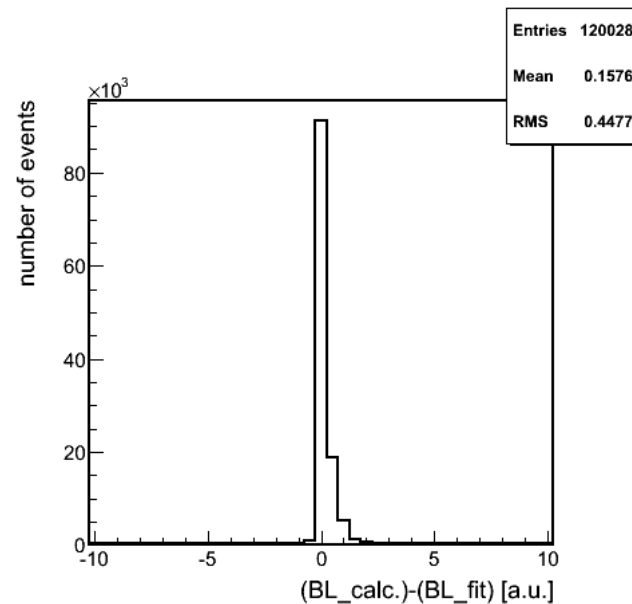
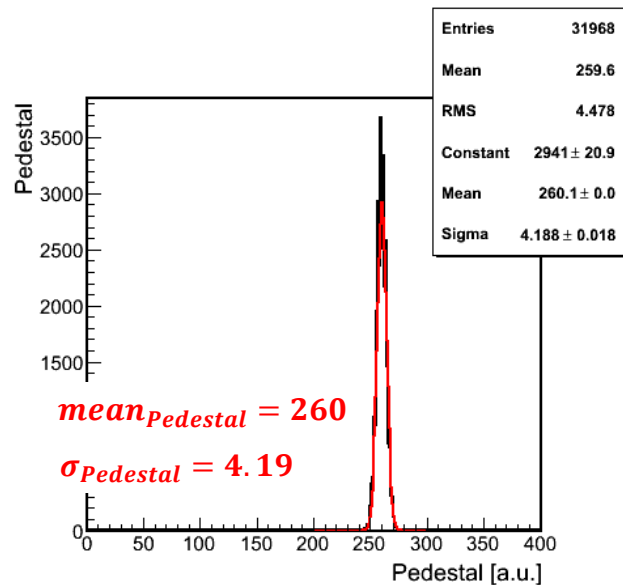
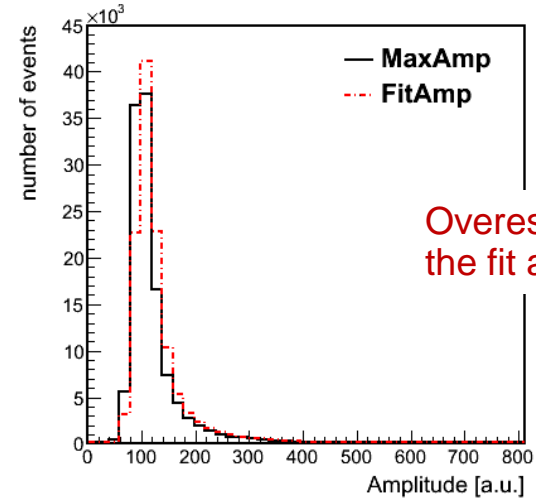
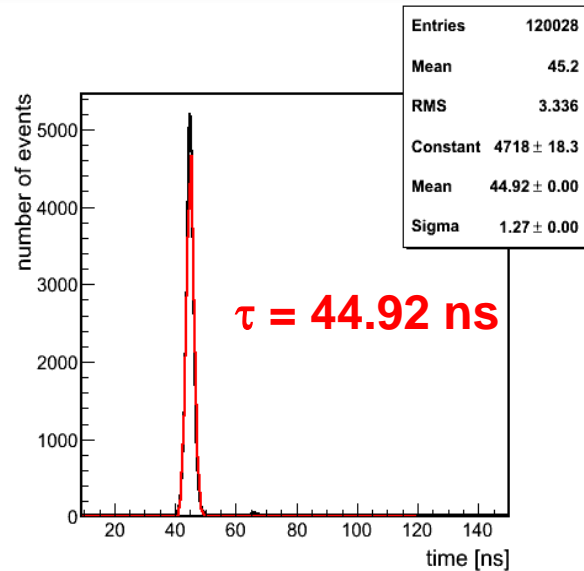
Channel 9 – Asynchronous Mode



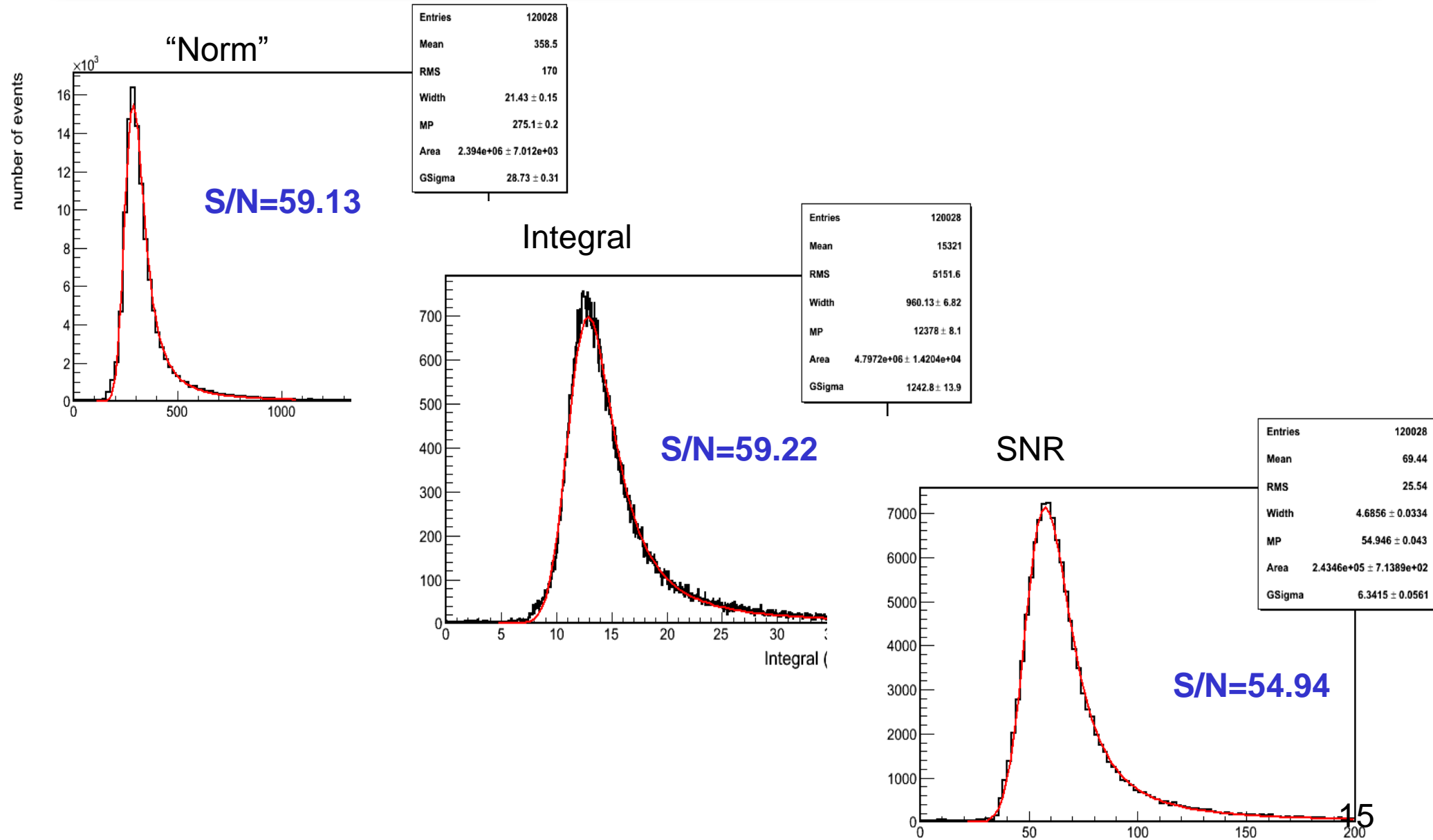
MPV_S/N = 67.06

Parameters distributions after the fit

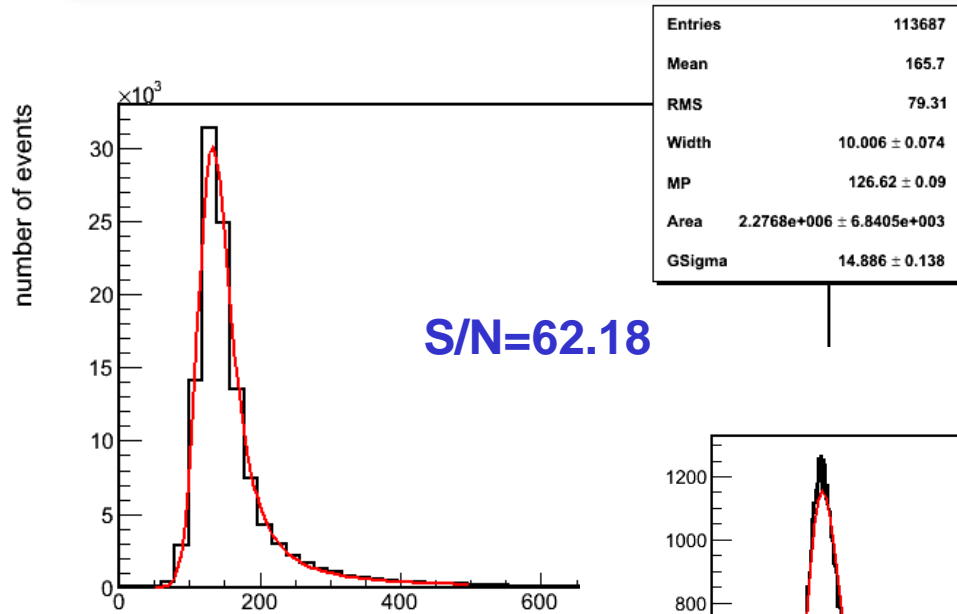
Channel 9 – Synchronous Mode



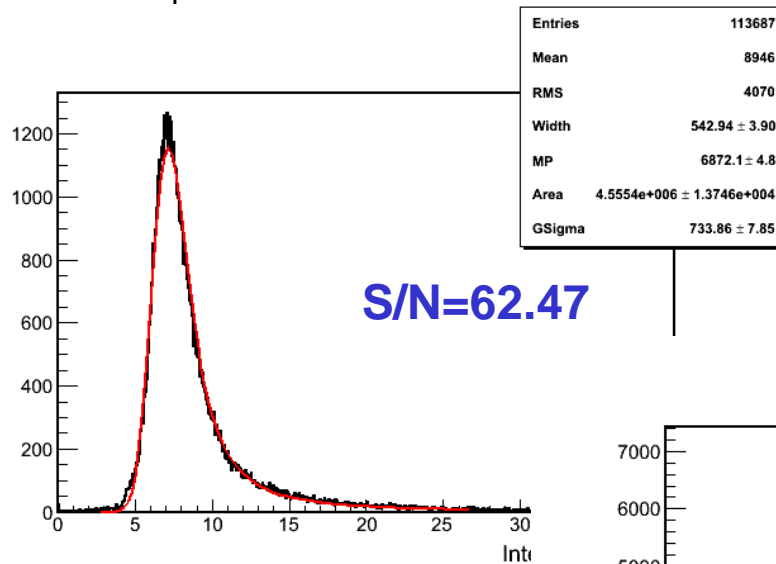
SNR: Channel 9 - Synchronous



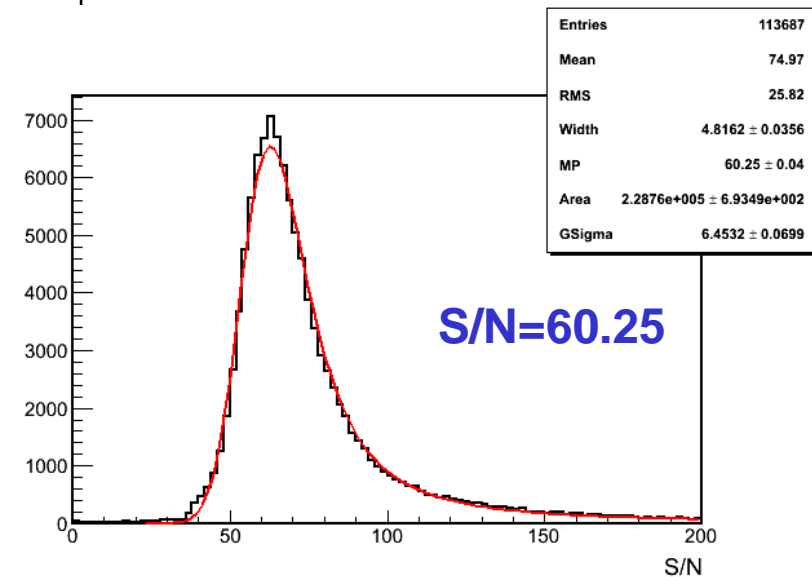
SNR: Channel 5 - Synchronous



S/N=62.18



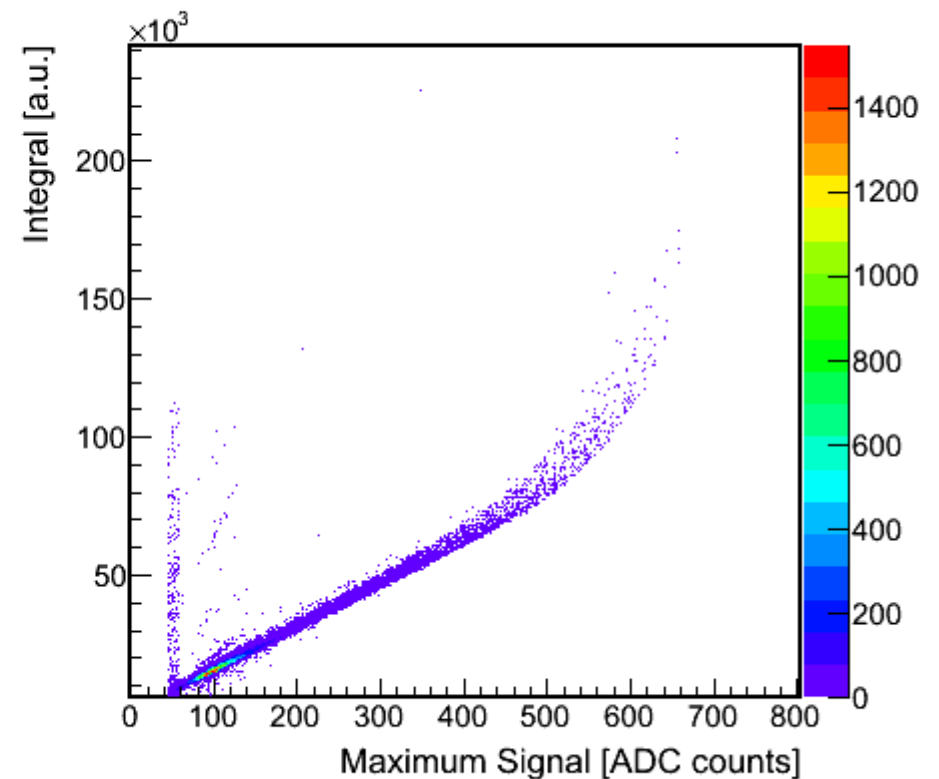
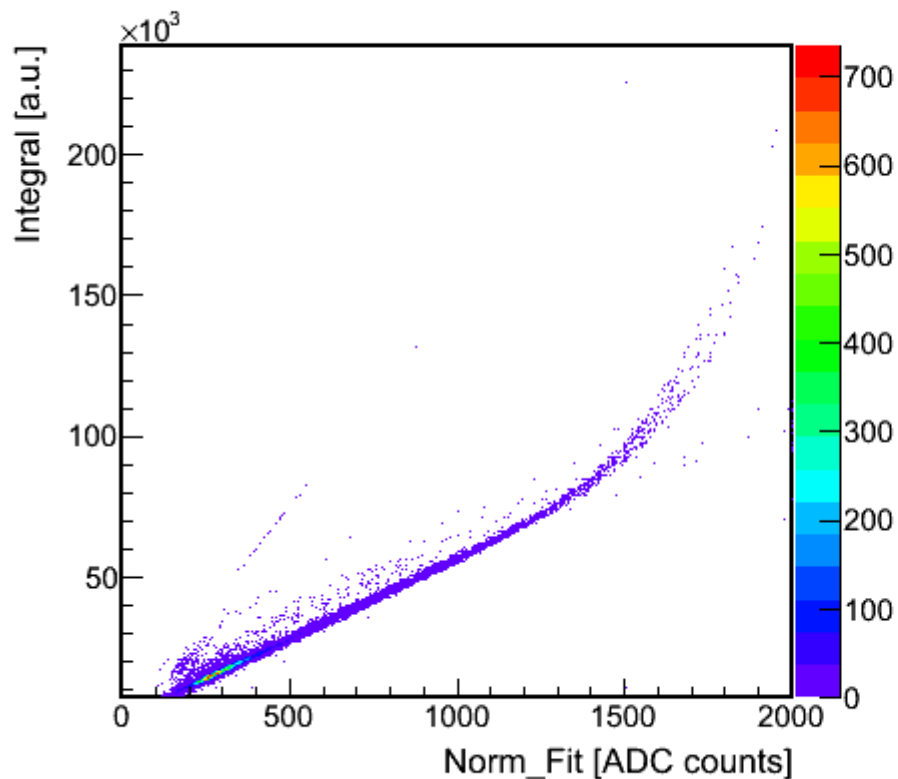
S/N=62.47



S/N=60.25

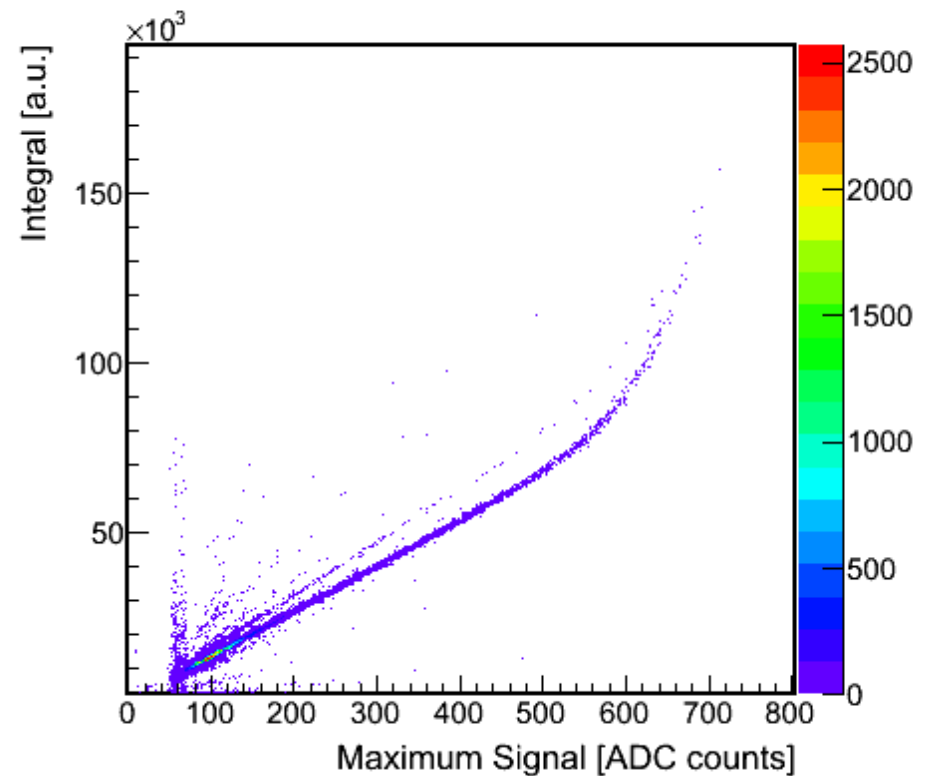
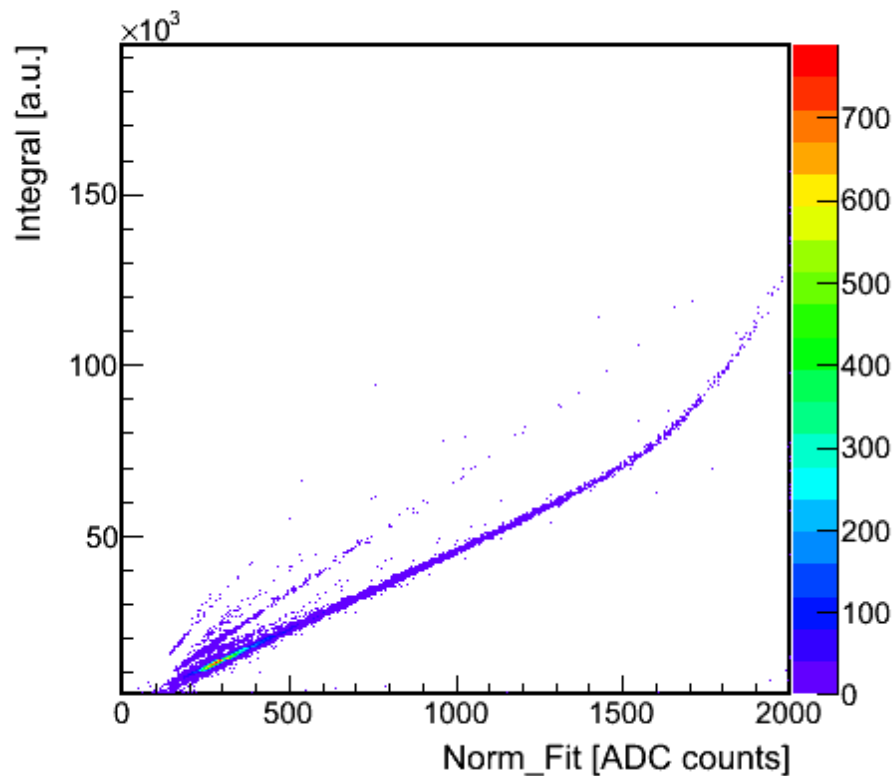
Correlations

Channel 9 – Asynchronous Mode



Correlations

Channel 9 – Synchronous Mode



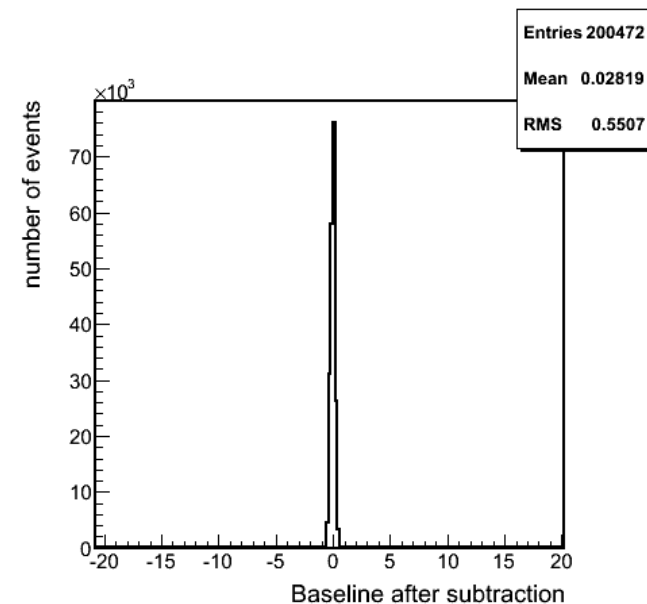
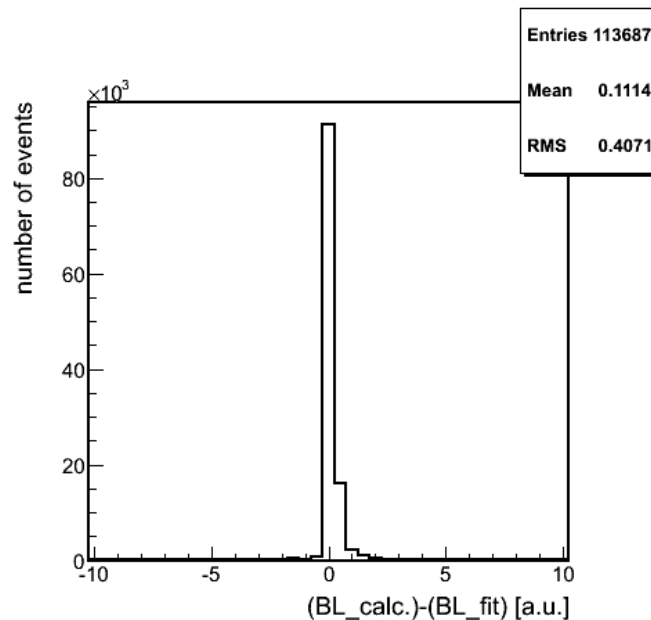
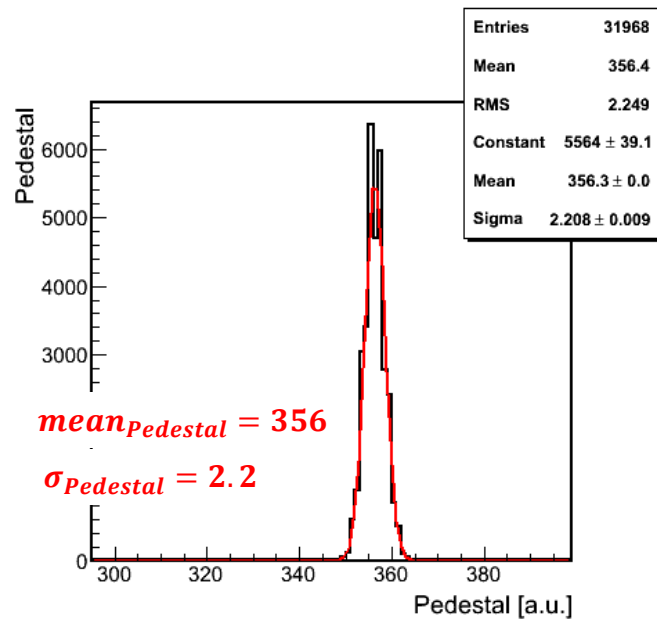
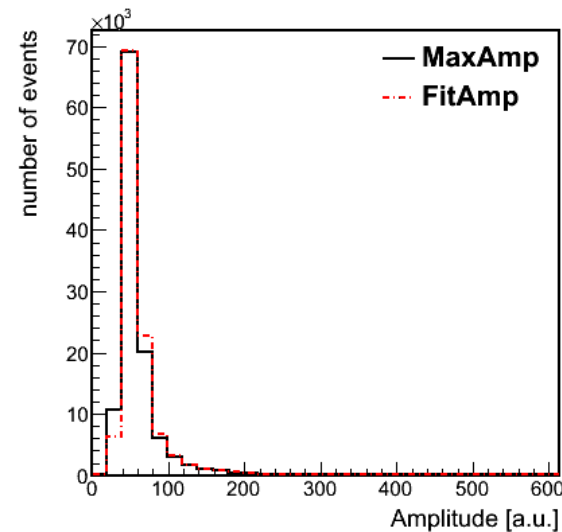
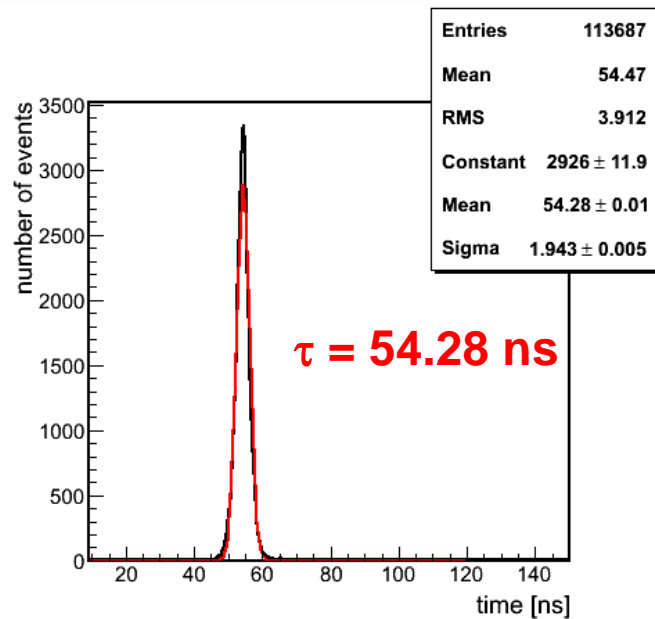
Conclusions

- Using the integration method, the SNR has been evaluated for two of the BeamCal module pads
 - Pad 10 (Channel 9) - high gain
 - Pad 6 (Channel 5) - low gain
- Channel 9- two cases:
 - Asynchronous mode
 - Synchronous mode
- SNR~67 for Channel 9 in sync mode
- SNR~59 for Channel 9 in async mode
- SNR~62 for Channel 5 in sync mode

Backup slides

Parameters distributions after the fit

Channel 5 – Asynchronous Mode



Correlations

Channel 5 – Asynchronous Mode

